



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Nikolay I. Agladze, Albert J. Sievers

Application No. : 10/720,763

Filed : November 25, 2003

For : Miniaturized Holographic
Fourier Transform
Spectrometer with
Digital Aberration
Correction

Group Art Unit No. 2877

Examiner:
Samuel A. Turner

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:


Pursuant to the provisions of 37 CFR 1.97 and 1.98, applicants hereby submit the documents listed on the attached PTO-1449A and PTO-1449B.

Copies of the cited publications are enclosed. Copies of the cited patents have not been included, but will be furnished upon request.

Respectfully submitted,

Nikolay I. Agladze, Albert J. Sievers
Applicant

JONES, TULLAR & COOPER, P.C.
Attorneys for Applicant


George M. Cooper
Reg No. 20,201

July 21, 2004
JONES, TULLAR & COOPER, P.C.
P.O. Box 2266 Eads Station
Arlington, Virginia 22202
(703) 415-1500
Attorney Docket: 10/720,763

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Complete if Known

Application Number	10/720,763
Filing Date	Even Date Herewith
First Named Inventor	Nikolay I. Agladze
Group Art Unit	2877
Examiner Name	Samuel A. Turner
Attorney Docket Number	CRF D-3094/US

Sheet	1	of	1
-------	---	----	---

[illegible][illegible]

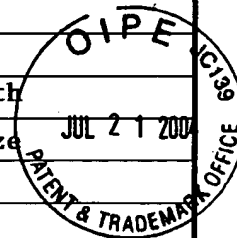
Date	
Considered	

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. **DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.**

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/720,763
				Filing Date	Even Date Herewith
				First Named Inventor	Nikolay I. Agladze
				Art Unit	2877
				Examiner Name	Samuel A. Turner
Sheet	1	of	1	Attorney Docket Number	CRF D-3094/US



NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	1	"Digital array scanned interferometer: sensors and results," Wm Hayden Smith and Philip D. Hammer; Applied Optics, Vol. 35, No. 16, 1 June 1996	
	2	"Photographic Method of Recording in Fourier Spectrometry," I.P. Petrov and B.N. Grechushnikov; Optics and Spectroscopy, 19, p. 82-83 (1965)	
	3	"Computational Aberration Correction for an Arbitrary Linear Imaging System," L. J. Allen, M. P. Oxley, and D. Paganin; Physical Review Letters, Vol. 87, No. 12, 17 September 2001	
	4	"Effects of aberrations on spatially modulated Fourier transform spectrometers," R. Glenn Sellar, J. Bruce Rafert; Optical Engineering, September 1994, Vol. 33, No. 9/3087	
	5	"Fourier transform spectrometer with a self-scanning photodiode array," Takayuki Okamoto, Satoshi Kawata, and Shigeo Minami; Applied Optics, 15 January 1984, Vol. 23, No. 2	
	6	"Spatially Encoded Fourier Transform Spectroscopy in the Ultraviolet to Near-Infrared," Jonathan V. Sweedler and M. Bonner Denton; Applied Spectroscopy, Vol. 43, No. 8, 1989	
	7	"Monolithic Fourier-transform imaging spectrometer," J. Bruce Rafert, R. Glenn Sellar, and Joel H. Blatt; Applied Optics, Vol. 34, No. 31, 1 November 1995	
	8	"Phase Retrieval through Focus Variation for Ultra-Resolution in Field-Emission Transmission Electron Microscopy," Wim Coene and Guido Janssen, Marc Op de Beeck and Dirk Van Dyck; Physical Review Letters, Vol. 69, No. 26, 28 December 1992	

Examiner Signature		Date Considered	
--------------------	--	-----------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 120 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.